







Towards Reliability Assurance of Deep Learning Systems

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Kyushu University

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Pangu Research Group

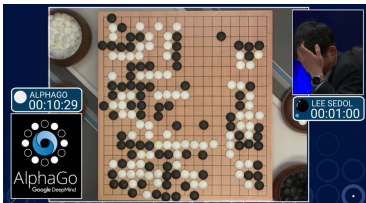
(<https://pangukaitian.github.io/pangu/en/index.html>)

- Our group focuses on researches on the potential symbioses between software engineering (SE) and artificial intelligence (AI)
- The overall goal is to obtain better software and AI systems, making them more **robust, reliable, and secure**, and **easier to specify, build, maintain, or improve**
- Our group consists of 2+ faculty members, 3 PhD students, and 7 master students


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Deep Learning Matches Human Intelligence

AlphaGo 4:1 Human Champion 2016




AlphaGo ZERO 100:0 AlphaGo 2017



LETTER

Run on - level control through deep reinforcement learning



ATARI 2600

At human level or above (Before Human level)

2015

2017

3

Rushing for Development and Real-world Deployment



Blog Post

Watson Health is committed to using AI to tackle major healthcare challenges



Driving Force of Many Novel Tech.



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Current Deep Learning is Vulnerable



Classified as panda

Small adversarial noise

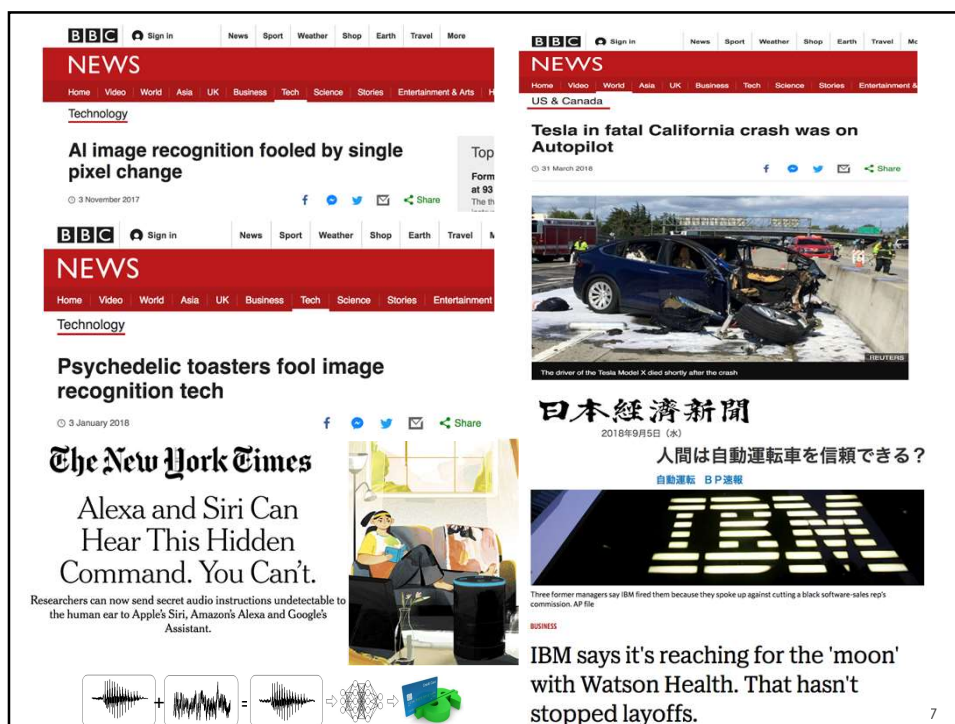
Classified as gibbon

Ian Goodfellow, Jon Shlens, Christian Szegedy, Explaining and Harnessing Adversarial Examples, ICLR, 2014



Accident

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Reliability Assurance for DL is at Early Stage

DeepXplore

SOSP'17

DeepTest

ICSE'18

ML Fairness Testing

ASE'18

DeepRoad

ASE'18

DeepConcolic

ASE'18



ASE'18

TensorFlow Program Bugs
ISSTA'18

MODE: DNN Debugging
FSE'18

Reliability Assurance for Traditional Software Testing Criteria and Tools

- Line Coverage
- Branch Coverage
- Function Coverage
- Data Flow Coverage
- Combinatorial Coverage
- Mutation testing Coverage
- ...

JACOBO
Java Code Coverage

Atlassian
Clover

NCOVER

Cobertura

µJava
pitest.org

EMMA

Major

EVASUITE

AgitarOne
AgitarOne (Java Test Tool)

K&K

Randoop

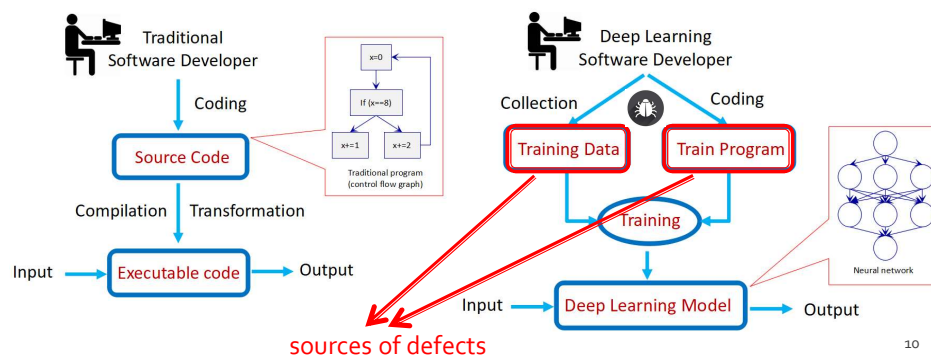
Pex

GRT
Test Apps Better

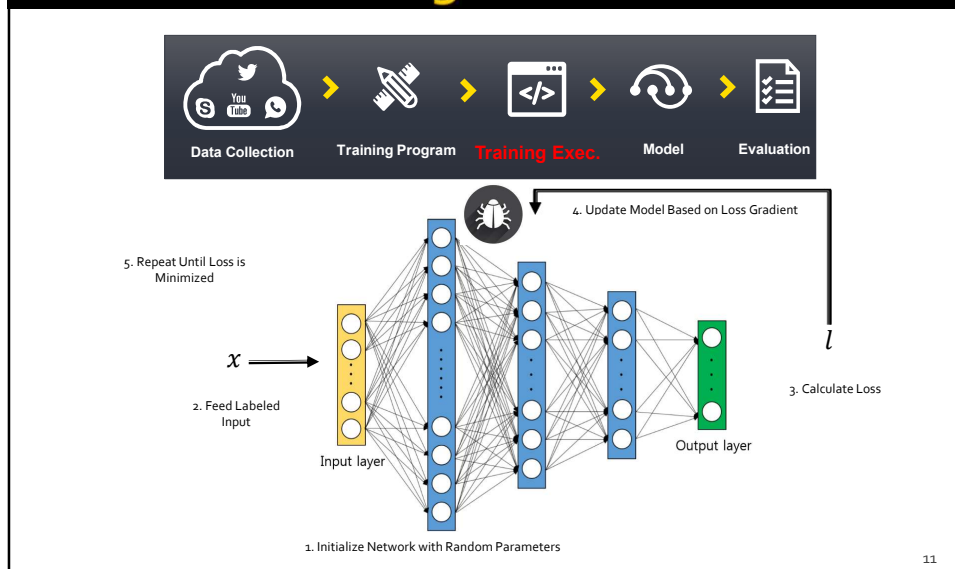
OCELOT

Source of Defects Programming Paradigm

- The decision logic of a traditional software:
 - In the form of code
- The decision logic of a DL system:
 - The structure of DNN
 - The connection weights

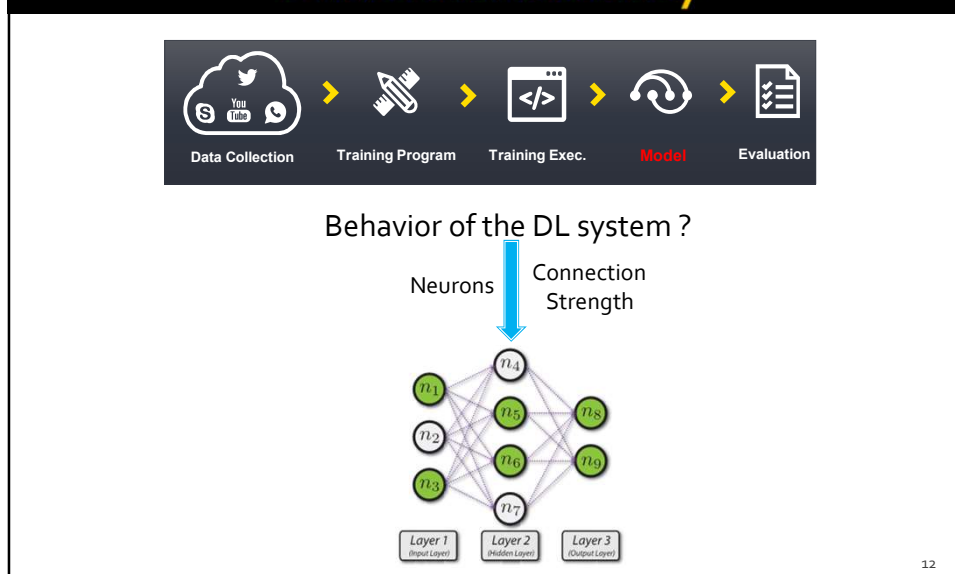


Source of Defects Training Procedure



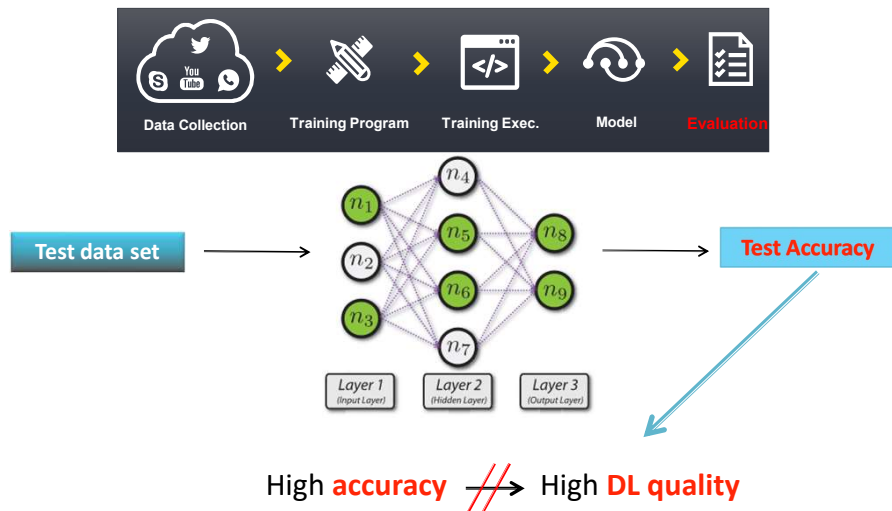
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Lacking of Interpretability and Understandability



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Reliability Measurement Immature



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Towards Reliability Assurance for Deep Learning Software

- Testing quality & logic coverage
- MT-based test data quality evaluation
- Combinatorial latent space exploration

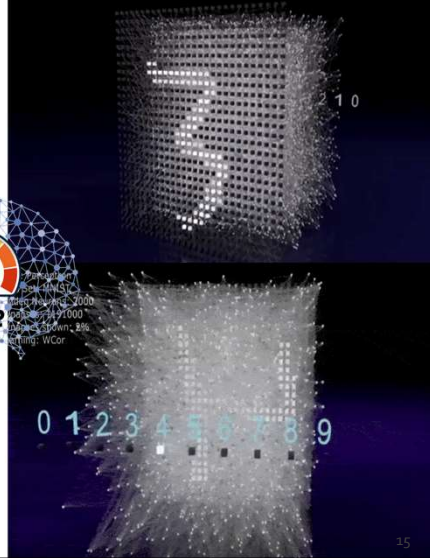


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Overview of DeepGauge (ASE2018)

Multi-Granularity Testing Criteria for Deep Learning Systems

- **Enable** quality evaluation of DLs from multiple portrayals
- **Provide** systematic guidance of TestGen for Defects
- **Facilitate** Interpretation & Understanding



Design of DeepGauge

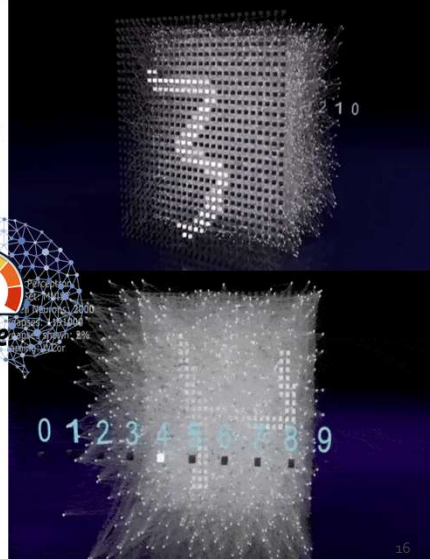
Simple to understand & use

Efficient to compute

General to diverse DNNs

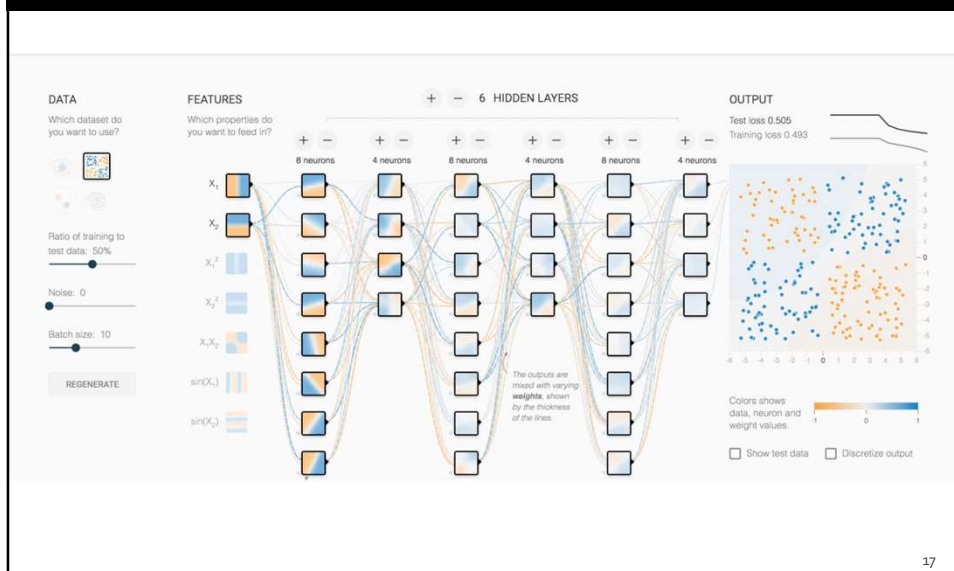
Scale to large DNNs

Adaptable by cases



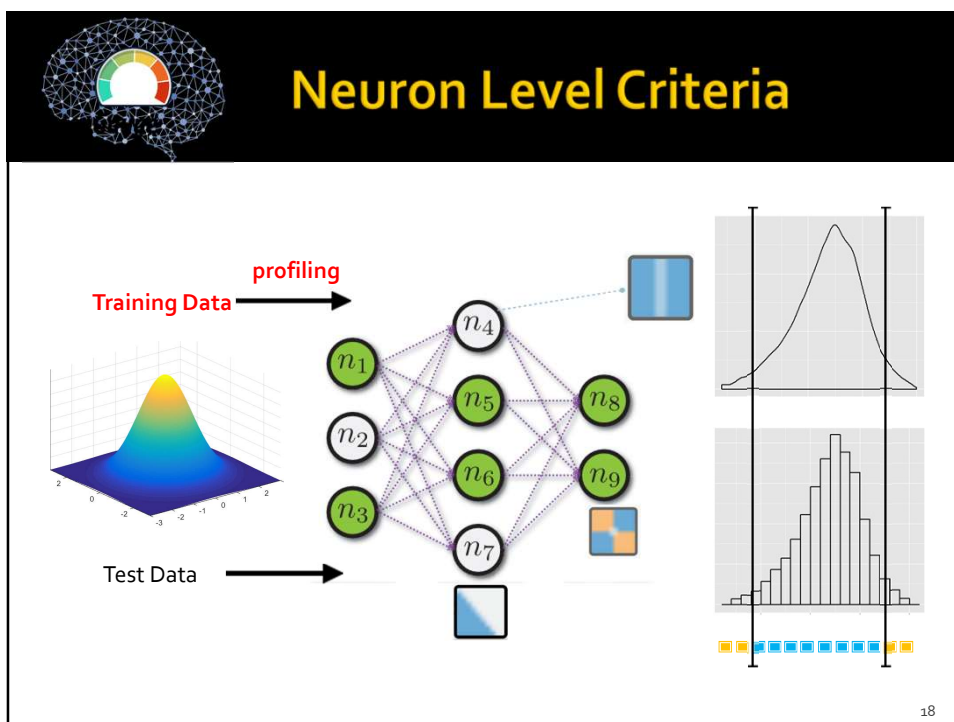
The Role of Neurons and Layers

(from TensorFlow Neural Network Playground)

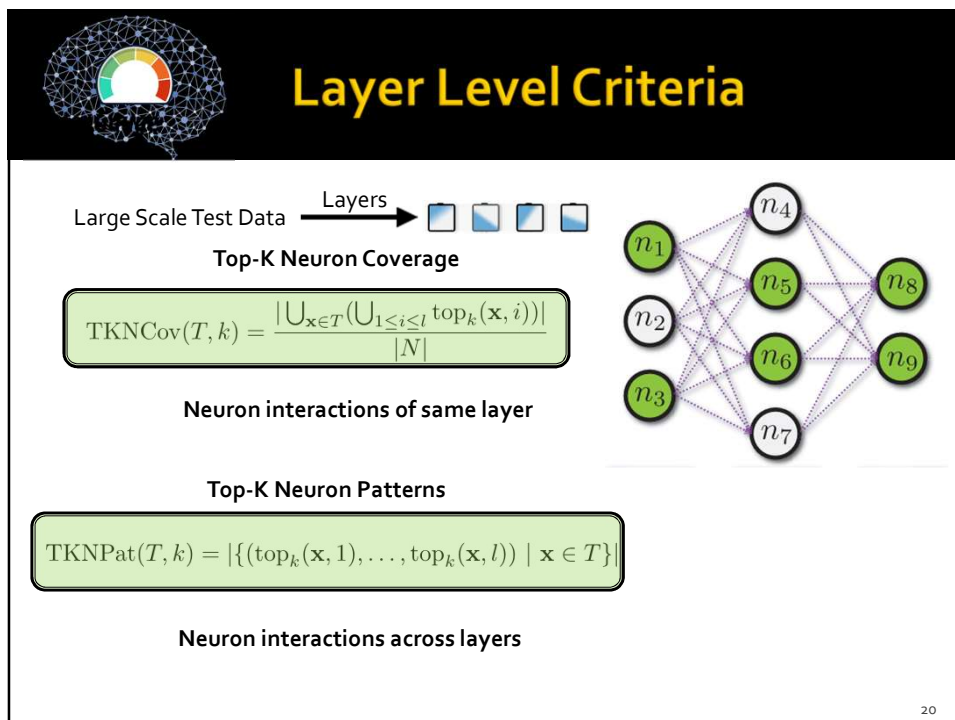
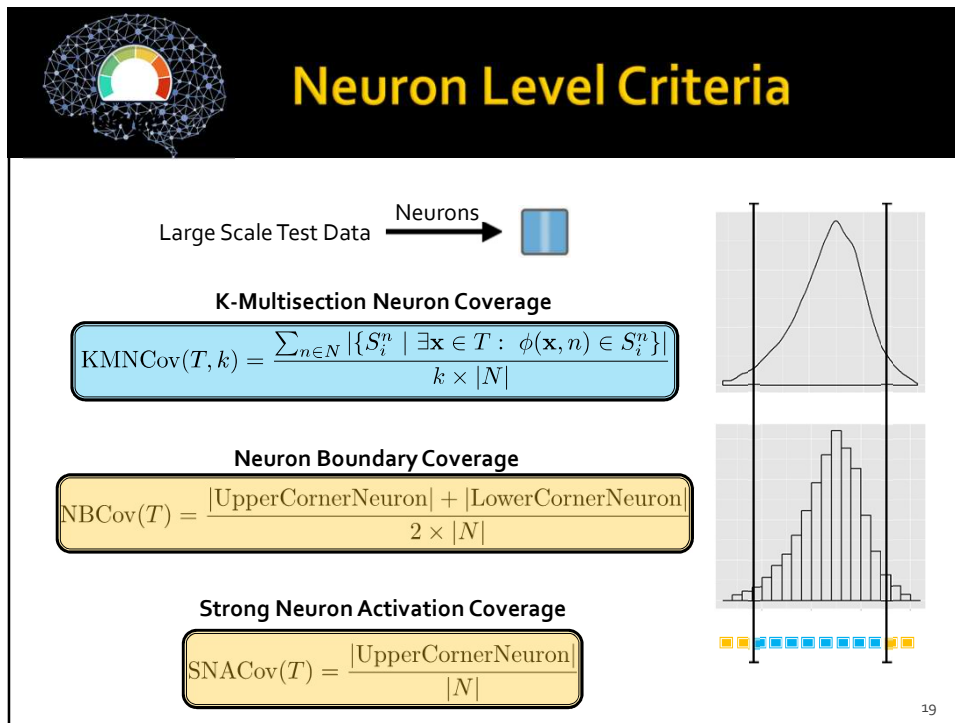


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Neuron Level Criteria



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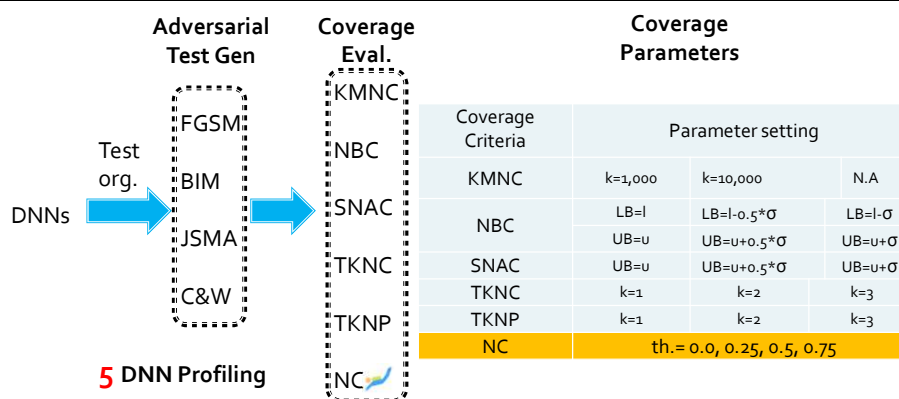
Large Scale Empirical Study

MNIST	DNNs	#Neurons	#Layers
60,000	LeNet-1	52	7
10,000	LeNet-4	148	8
(28,28,1)	LeNet-5	268	9
784 dim.	VGG-19	16,168	25
	ResNet-50	95,059	176

IMAGENET (LSVRC-2012)	DNNs	#Neurons	#Layers
1,000,000+	LeNet-1	52	7
50,000	LeNet-4	148	8
(224,224,3)	LeNet-5	268	9
150528 dim.	VGG-19	16,168	25
	ResNet-50	95,059	176

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Large Scale Empirical Study



5 DNN Profiling

18 Group Large Scale Adv Test Gen

190,000 Test data= 150,000 (MNIST) + 40,000 (ImageNet)

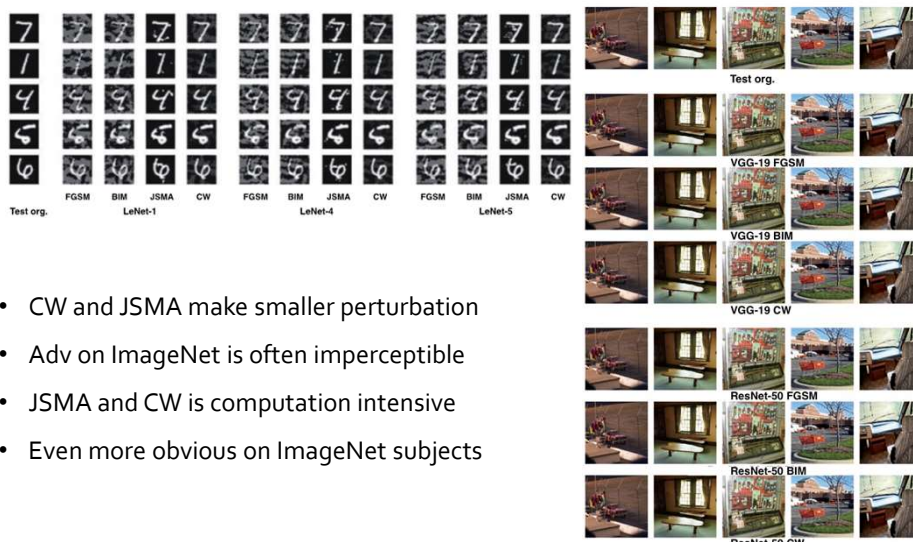
414 Evaluation Configurations= 270 (MNIST) + 144 (ImageNet)



Tesla M40 GPU 24GB / 18-core 2.3GHz Xeon 64-bit 196 GB

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Adversarial Examples



- CW and JSMA make smaller perturbation
- Adv on ImageNet is often imperceptible
- JSMA and CW is computation intensive
- Even more obvious on ImageNet subjects

DeepMutation: Mutation Testing of Deep Learning System (ISSRE'18)

DeepMutation: Mutation Testing of Deep Learning Systems

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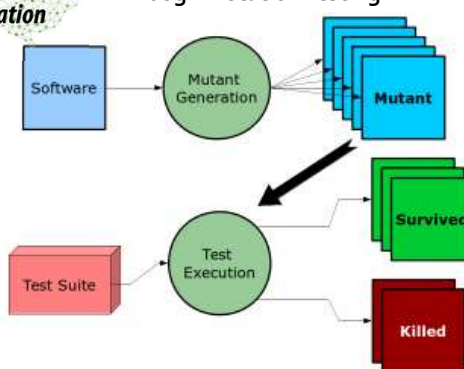
arXiv:1805.05206v2 [cs.LG] 14 Aug 2018

Abstract—Deep learning (DL) defines a new data-driven processing paradigm where the internal structure is largely shaped by the training data. The standard way of evaluating DL models is to compare their performance on a test dataset. The quality of the test dataset is of great importance to the confidence of the current results. Being an independent and different DL model that has achieved high test performance may still have imperceptible and subtle differences from the original model, which may affect the quality evaluation of test cases, which may lead to false conclusions. In this paper, we propose a new method to evaluate the quality of test data by introducing mutation testing into DL systems. We first design a set of novel mutation operators to inject faults into the DL models. Then, we design a set of novel mutation operators to inject faults into the DL models. Finally, we design a set of novel mutation operators to inject faults into the DL models. The quality of test data can be evaluated from the results of the mutation testing. The quality of test data can be evaluated from the results of the mutation testing. The quality of test data can be evaluated from the results of the mutation testing.

1. INTRODUCTION
Over the past decade, deep learning (DL) has achieved tremendous success in many areas, including image classification, speech recognition, and machine translation [1]. The success of DL is largely due to the availability of large-scale training data and the development of powerful DL models. However, the quality of the training data is often overlooked. In this paper, we propose a new method to evaluate the quality of test data by introducing mutation testing into DL systems. We first design a set of novel mutation operators to inject faults into the DL models. Then, we design a set of novel mutation operators to inject faults into the DL models. Finally, we design a set of novel mutation operators to inject faults into the DL models.

2. RELATED WORK
Mutation testing is a well-known software testing technique. It involves making small changes (mutations) to the source code of a program and then running the program to see if the mutations are detected. In the context of DL, mutation testing can be used to evaluate the quality of the training data. By injecting faults into the training data, we can see how well the DL model is able to detect these faults. This can help us to identify areas where the training data is of poor quality and needs to be improved.

Testdata Quality Assessment Through Mutation Testing



Combinatorial Testing

DeepCT

Combinatorial Testing for Deep Learning Systems

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Abstract. Deep learning (DL) has achieved remarkable progress over the past decade and has been widely applied to many sophisticated applications. However, the robustness of DL systems mostly remains an open question, such as adversarial examples against computer vision systems, which could potentially result in severe consequences. Adopting testing techniques could help to evaluate the robustness of a DL system and therefore detect vulnerabilities at an early stage. The main challenge of testing such systems is that its runtime state space is too large; if we view each neuron as a runtime state for DL, then a DL system could evaluate massive states, making testing such state almost impossible. For traditional software, combinatorial testing (CT) is an effective testing technique to reduce the testing space while obtaining relatively high defect detection abilities. In this paper, we perform an exploratory study of CT on DL systems. We adapt the concept of CT and propose a set of coverage criteria for DL systems as well as a CT coverage guided test generation technique. Our evaluation demonstrates that CT works as a promising avenue for testing DL systems. We further pose several open questions and interesting directions for combinatorial testing of DL systems.

Keywords: Combinatorial testing, Deep learning, Adversarial attacks

1 Introduction

Deep learning (DL) systems have been widely applied in various applications due to their high accuracy, such as computer vision [35], natural language processing [30], and autonomous driving [5], and industrial control diagnosis [33]. However, recently DL systems have been shown to be vulnerable against different attacks, such as adversarial examples in computer vision and audio systems. Given that most real-time safety-critical applications start to adopt DL, exploring DL without thorough testing to safety-critical applications can lead to severe consequences, such as possible accidents in autonomous driving [33]. DL systems are

- Neuron Activation Configuration
- T-way combination sparse coverage
- T-way combination dense coverage
- (p,t)-completeness coverage

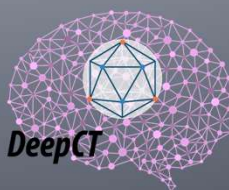
Parameters	All Combinations	2-Pair (Pairwise)
P1 : A , B , C		
P2 : 1 , 2		
P3 : X , Y		
	TC1 : A 1 X	TC1 : A 1 X
	TC2 : A 1 Y	TC4 : A 2 Y
	TC3 : A 2 X	TC6 : B 1 Y
	TC4 : A 2 Y	TC7 : B 2 X
	TC5 : B 1 X	TC9 : C 1 X
	TC6 : B 1 Y	TC12 : C 2 Y
	TC7 : B 2 X	
	TC8 : B 2 Y	
	TC9 : C 1 X	
	TC10 : C 1 Y	
	TC11 : C 2 X	
	TC12 : C 2 Y	

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NVIDIA AI Tech Center (NVAITC)

10+ Nvidia Tesla M40, 20 Tesla V100



<http://deepgauge.github.io/>